

FNAL work shop

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HPK Low Gain Avalanche Detector

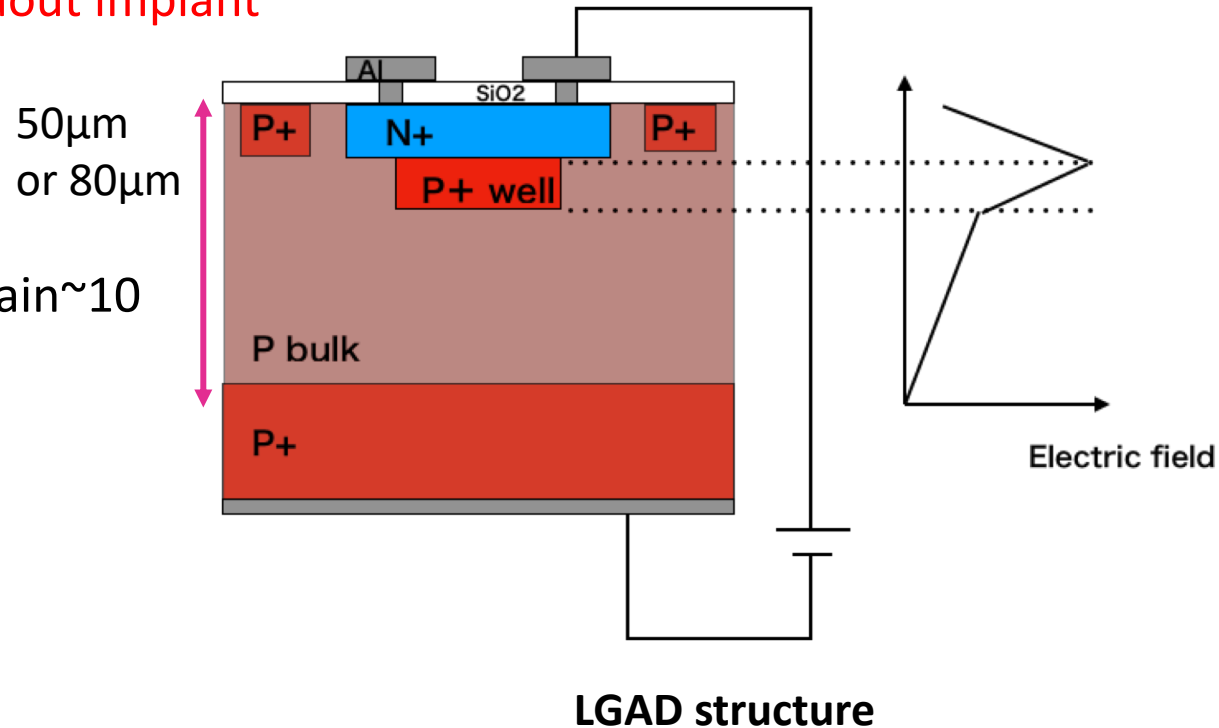
- N+ in P type silicon detector
- P+ layer under N+ readout implant
->high electric field



- Avalanche
 - High S/N ratio @gain~10
 - Thinner detector



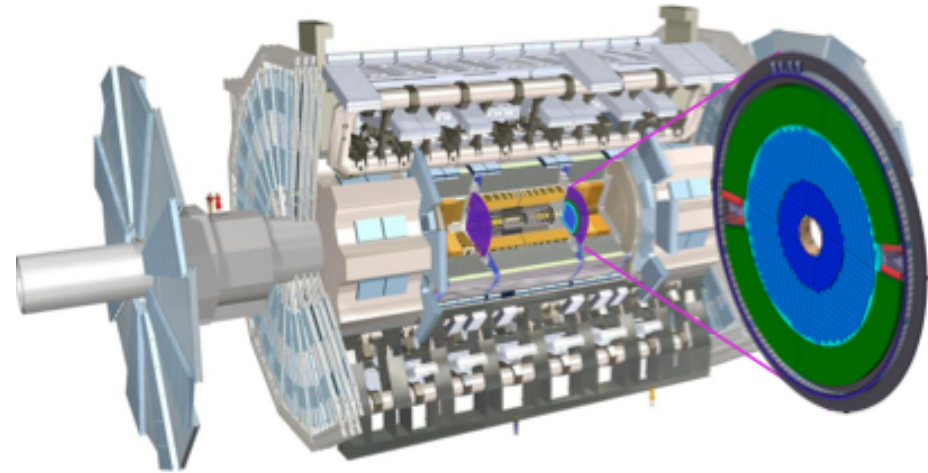
- Time resolution ~30ps



Practical use of LGAD

■ High-Granularity Timing Detector

- Detector for ATLAS(HL-LHC)
- Timing information for track
->improves the track-to-vertex
association
(even with the high pile-up)

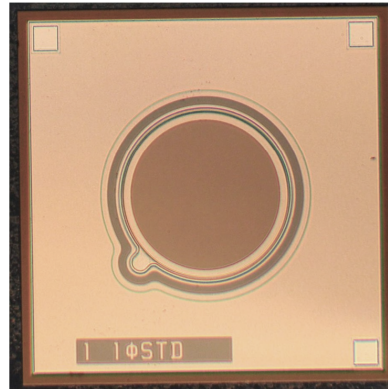


ATLAS Detector and HGTD

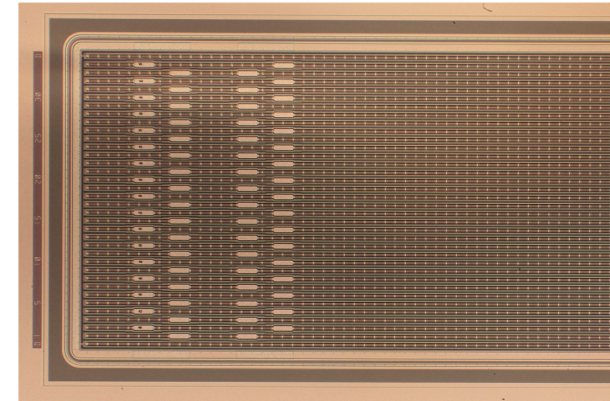
■ Positron Emission Tomography

- cancer diagnosis, neuroimaging and molecular imaging research.
- High time resolution
->Discover cancer with high positional resolution

HPK Samples



Pad detector



Strip detector

■ Pad

- Size: 2.5mm × 2.5mm
- Opening window: 1mm ϕ

■ Strip

- Size: 6mm × 12mm
- Strip pitch 80 μ m

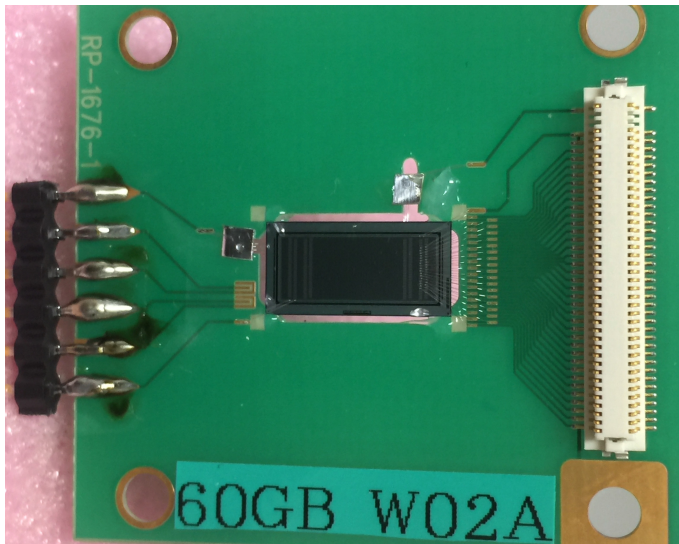
■ Irradiation

- γ irradiation 0.1, 1.0, 2.5 MGy
- n irradiation 0.3, 1.0, 3.0 $\times 10^{15}$
1MeVn_{eq}/cm²

Sample name	P+ dose A<B<C<D	Physical thickness	Active thickness
50A	A	150	50
50B	B		
50C	C		
50D	D		
80A	A		80
80B	B		
80C	C		
80D	D		

Measurement of basic characteristics

- Samples wire bonded on print circuit board
 - measured at 20°C(nonirrad), -20°C(irrad)
- IV
 - Bulk capacitance
 - Charge collection



Sample on PCB

thermostat



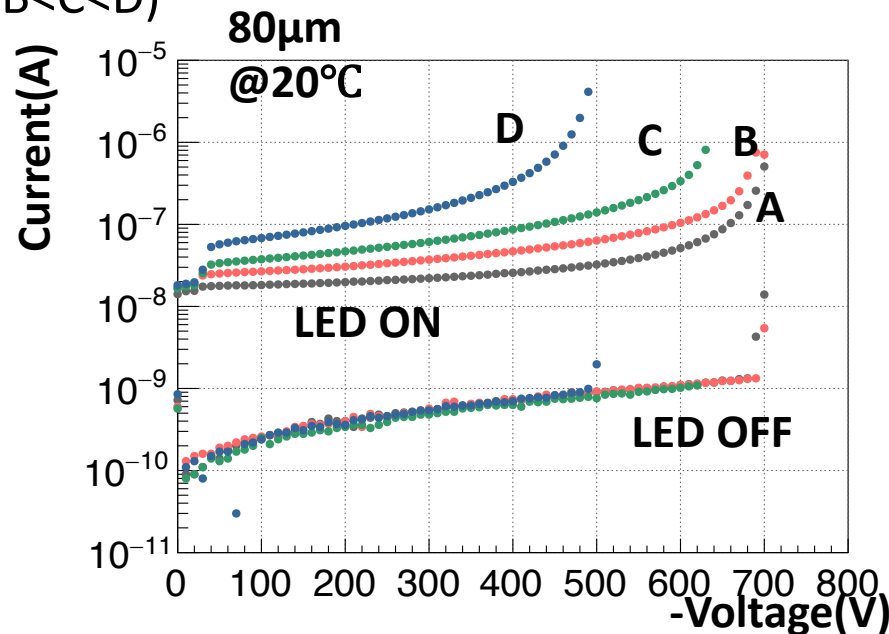
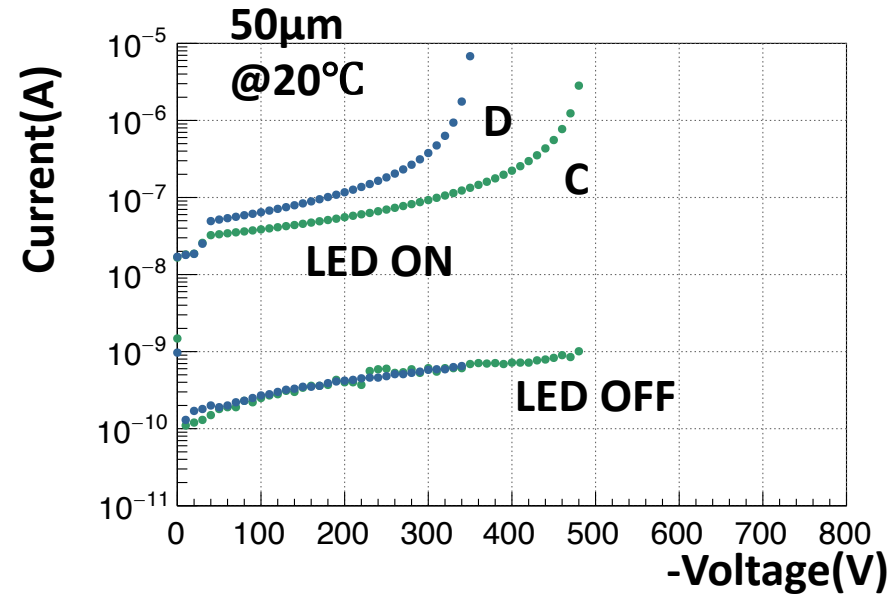
Pad Sensor IV

■ Leakage (LED OFF)

- Independent of P+ concentration
- All samples \sim nA

■ IR LED response (LED ON)

- P+ concentration dependence ($A < B < C < D$)
 - Higher(D)
 - > larger gain @ lower voltage
 - > breakdown @ lower voltage
- Active thickness dependence
 - 50 μ m
 - > breakdown, gain @ lower voltage



IV after γ -ray irradiation

■ 24 Nov.- 20 Dec. 2016 @ QST, Takasaki, Japan

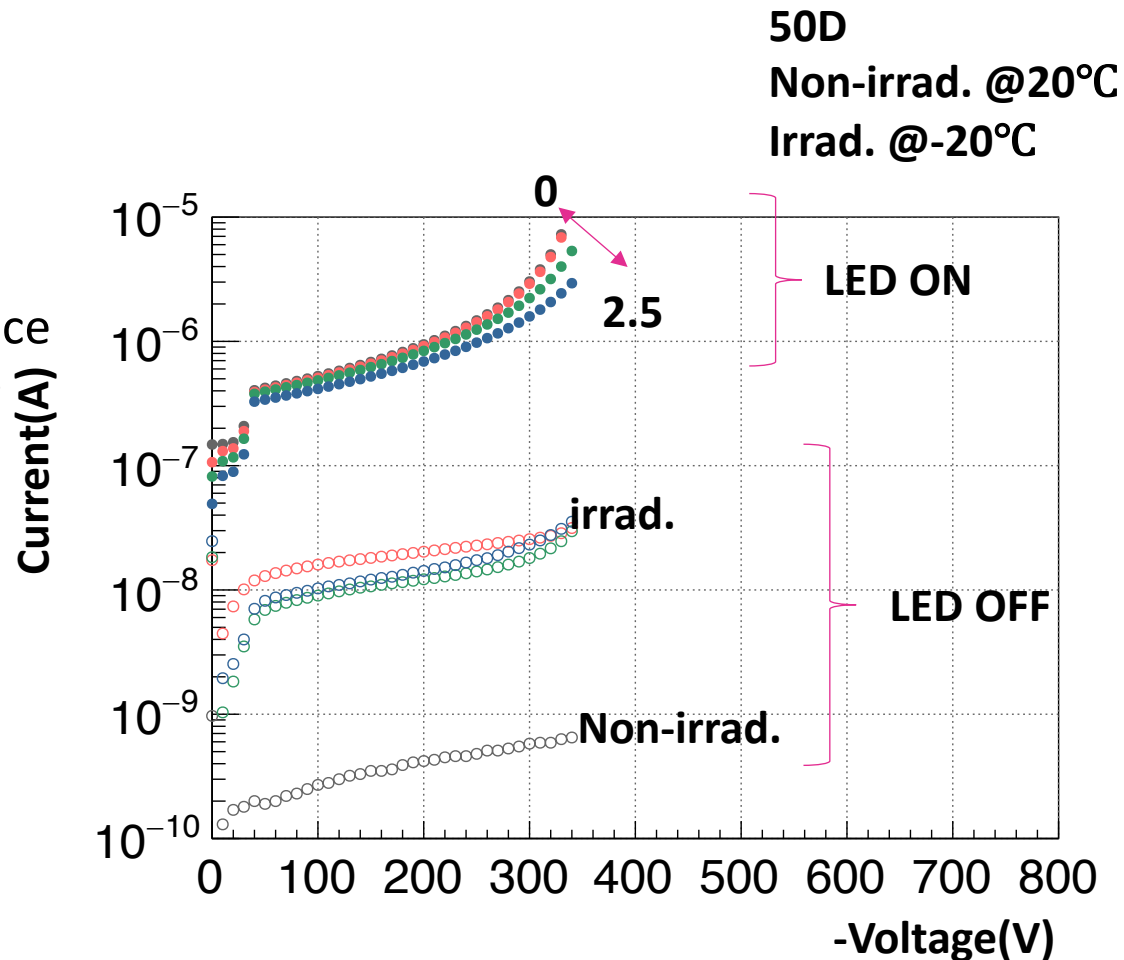
- 0.1/ 1.0/ 2.5 MGy

■ Leakage(LED OFF)

- Increases but no dose dependence
->only surface damage

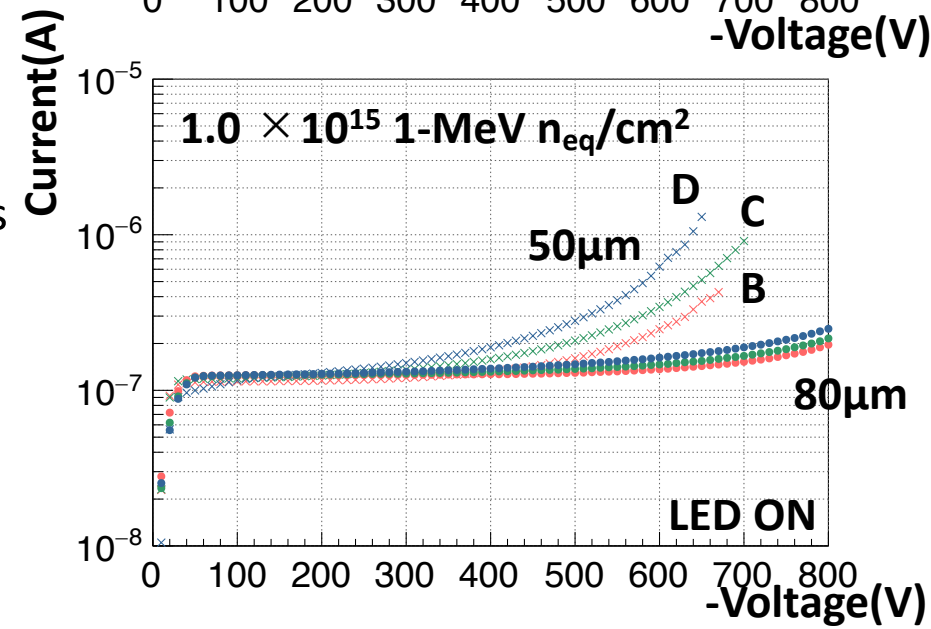
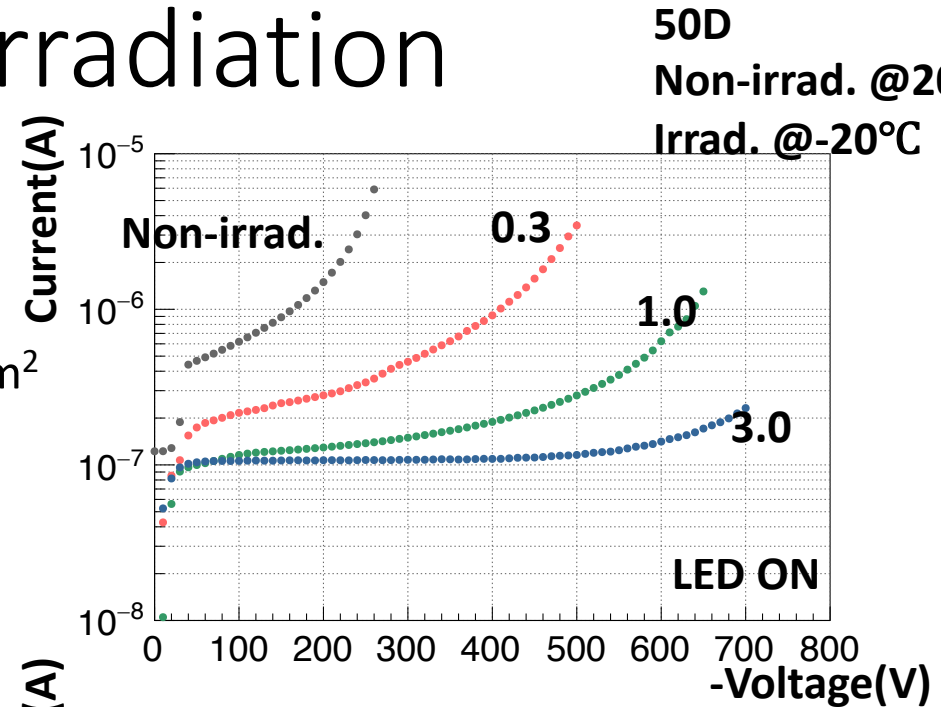
■ Gain

- Not degraded significantly



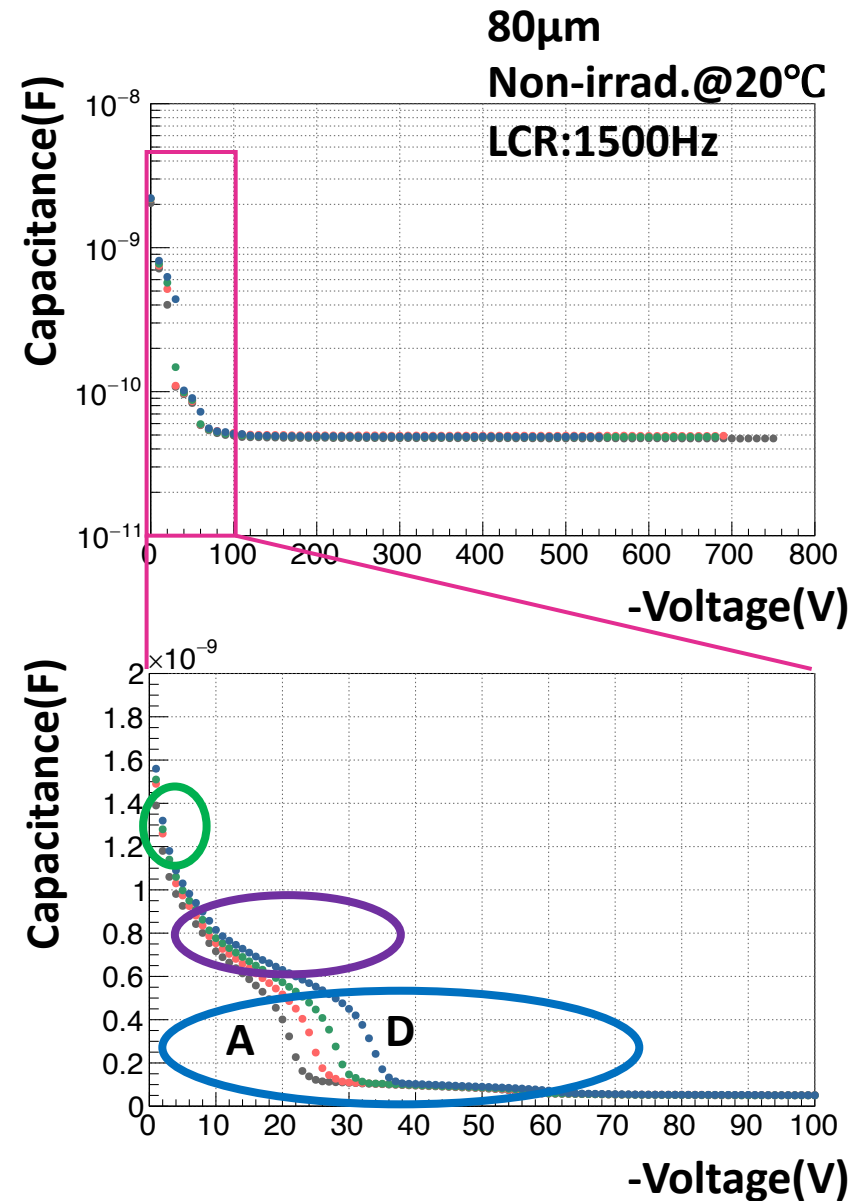
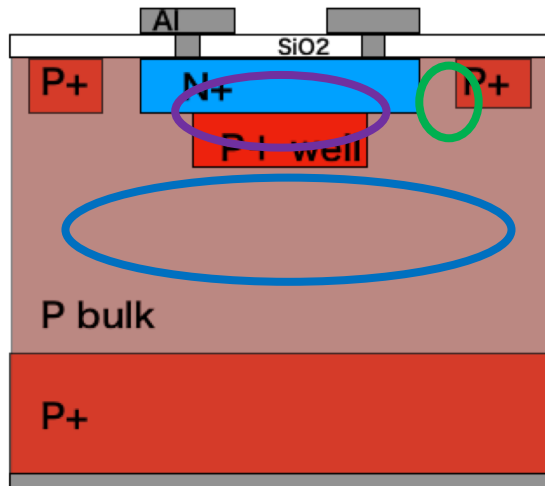
IV after neutron irradiation

- 15 Dec. 2016 @Ljubljana, Slovenia
 - $0.3/ 1.0/ 3.0 \times 10^{15}$ 1-MeV n_{eq}/cm^2
 - After $60^\circ C$, 80min. Annealing
- Gain
 - Degraded depend on fluence
-> requires higher voltage to retain same gain
- P+ concentration and active thickness
 - More gain for
 - Higher concentration
 - thinner



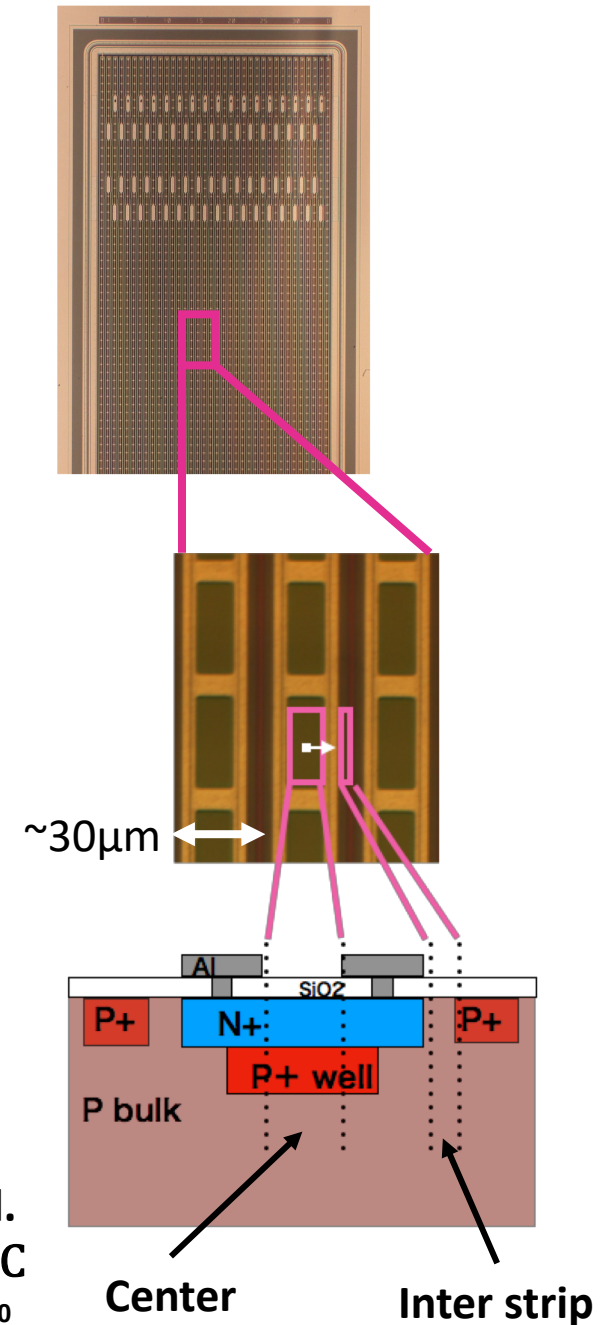
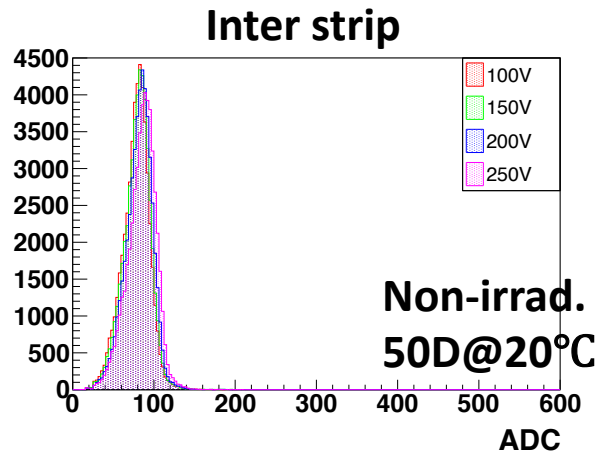
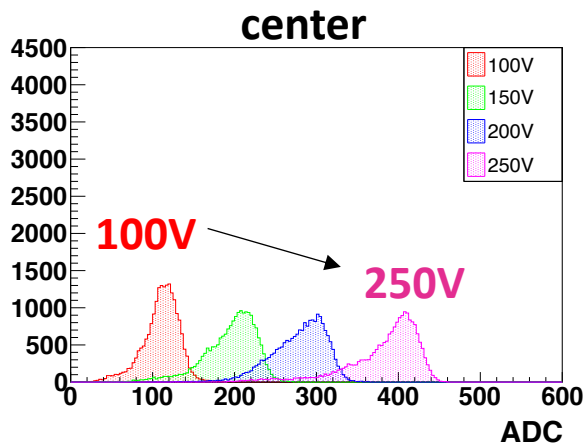
Bulk capacitance

- Full depletion Voltage
 - 25(80A) -35V(80D)
- Depletion steps
 1. Side regions
 2. Multiplication region
->more p+ concentration,
higher depletion voltage
 3. bulk



Charge collection

- Gain evaluation by charge collection
 - Measured using Alibava system
 - incident IR-Laser (spot size $2\mu\text{m} \times 2\mu\text{m}$)
→ uniformly generate h-e pairs
 - Center region
 - Charge collection increase with bias
 - Inter strip region
 - Charge collection stays constant



Gain

■ Evaluation of gain

$$Gain(V) = \frac{ADC(V)}{ADC(50V@inter\ strip)}$$

■ Dependence on bias voltage

- Gain increases with bias voltage

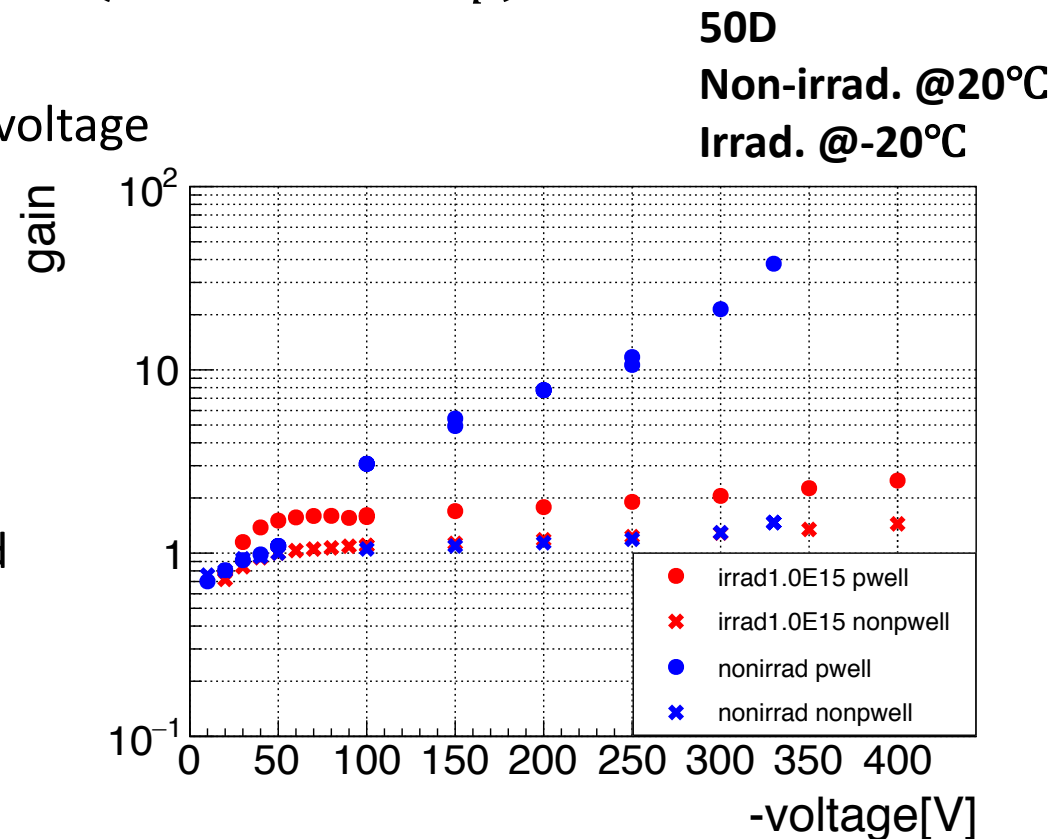
■ Non-irrad.

- Gain ~ 10 @ 250V

■ Neutron irradi.

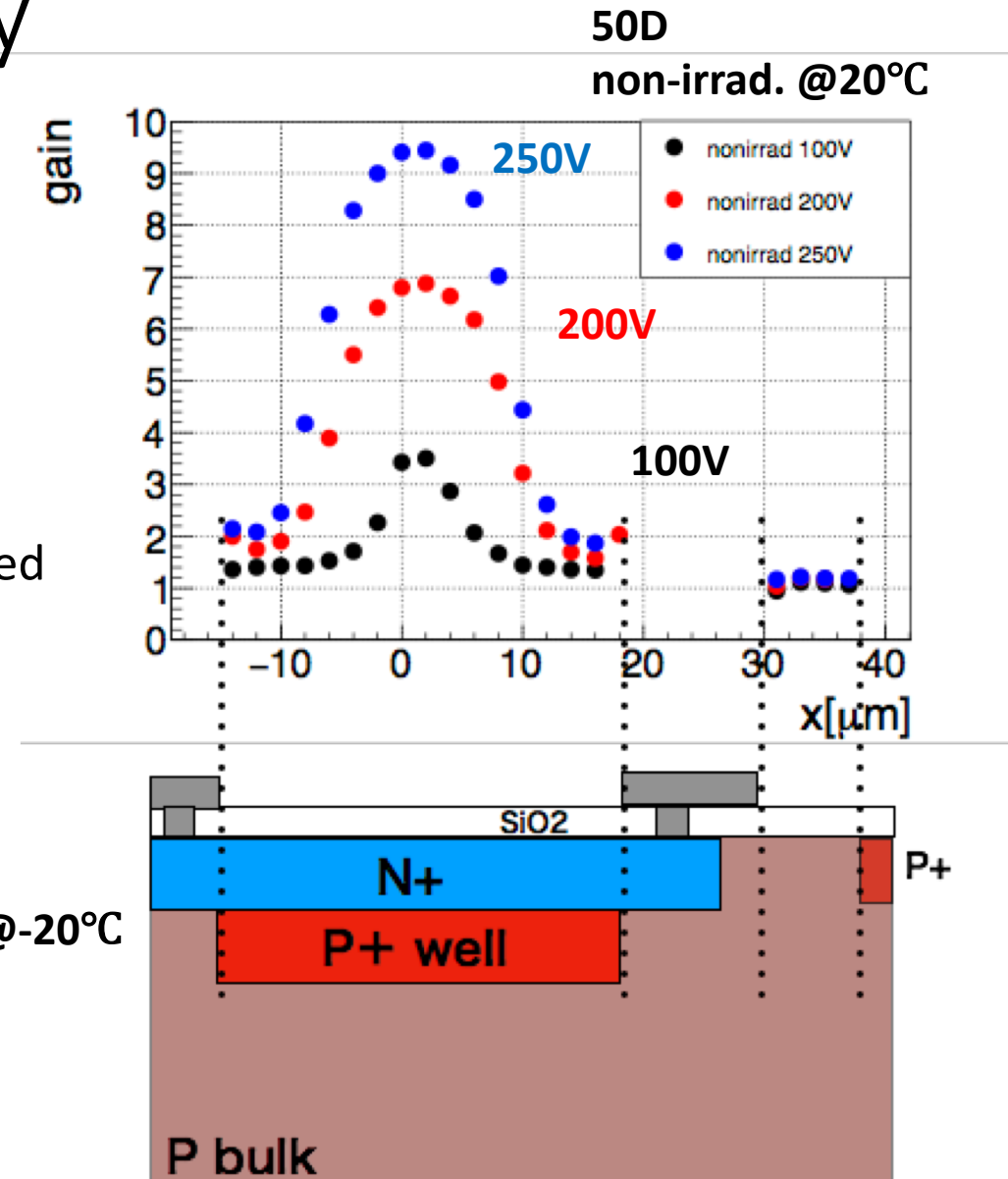
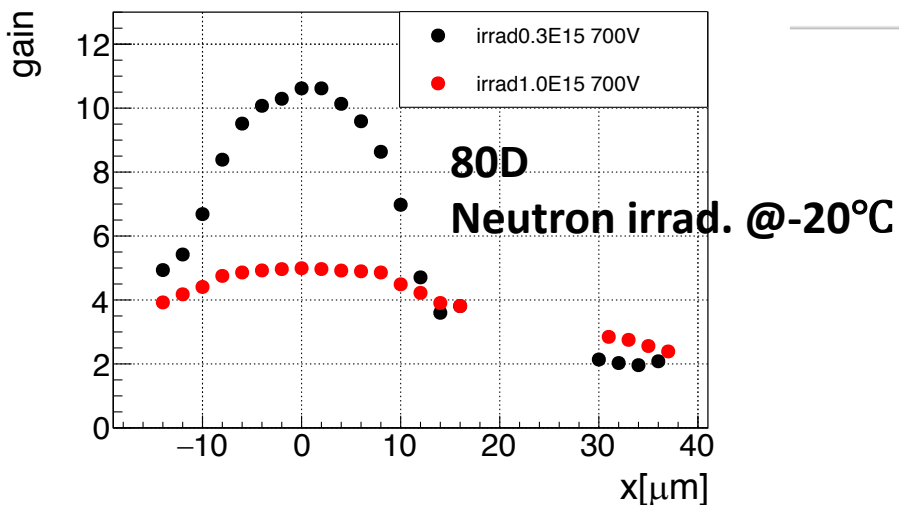
(1.0×10^{15} 1-MeV n_{eq}/cm^2)

- Gain ~ 2.5 @ 400V
->higher voltage required for gain~10



Gain uniformity

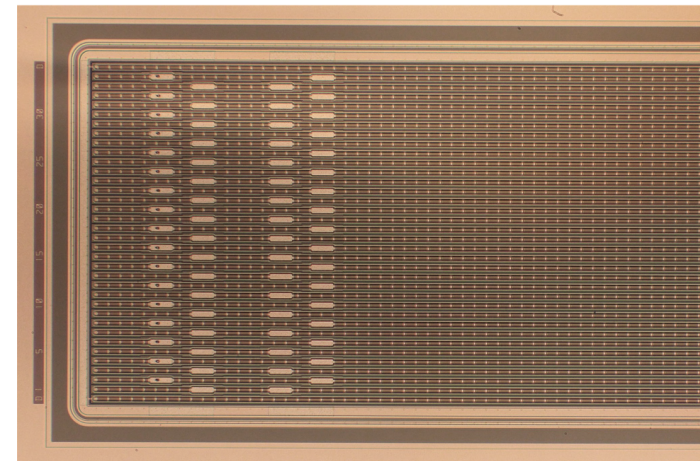
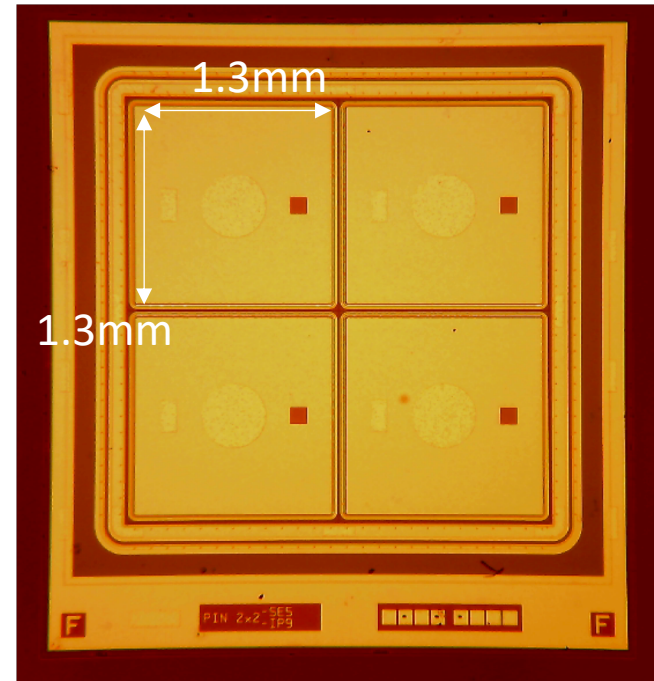
- Gain dependent on incident position of IR laser
- uniformity dependent on bias voltage
- After neutron irradiation.
 - Uniformity seems improved (gain in inter strip region)



FNAL test beam 2019/02

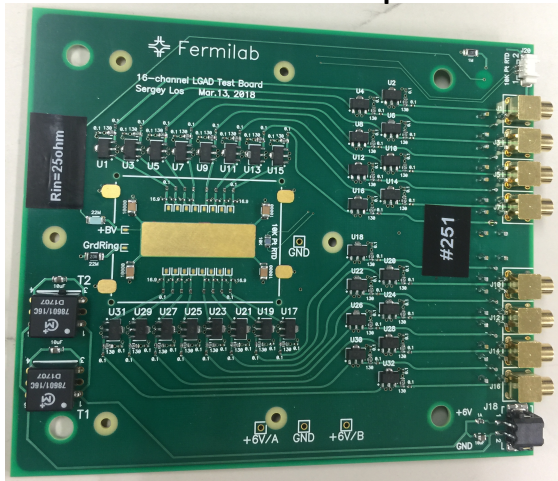
■ Samples

- 2x2 array pad(stack two sensor)
 - Size: 1.3mm × 1.3mm
 - Time resolution
 - >Compare to another sensor
- Strip
 - HPK 50D
 - Position dependence of Pulse height
 - >Gain uniformity

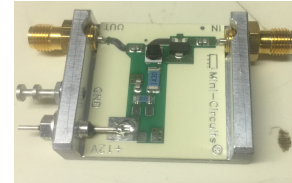


FNAL test beam set up

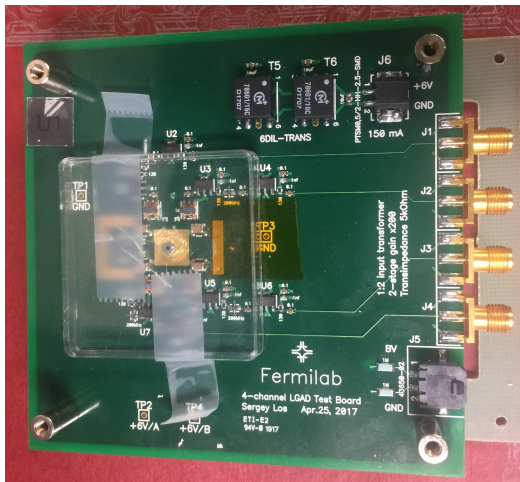
Strip + 16ch. amp



External amplifier(x3)



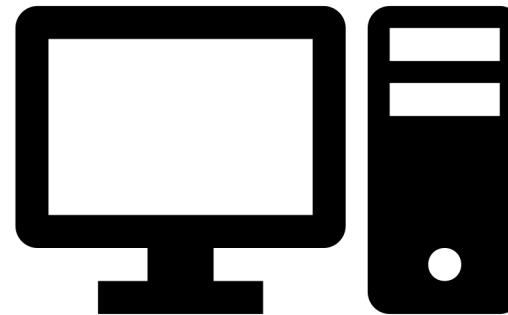
2x2 array (x2) + 4ch. amp



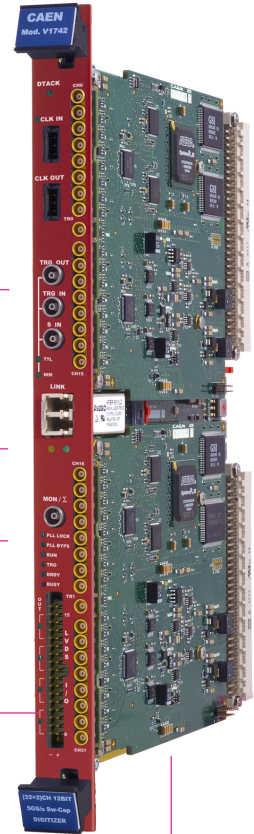
data

TRG

Seabus TLU



PC

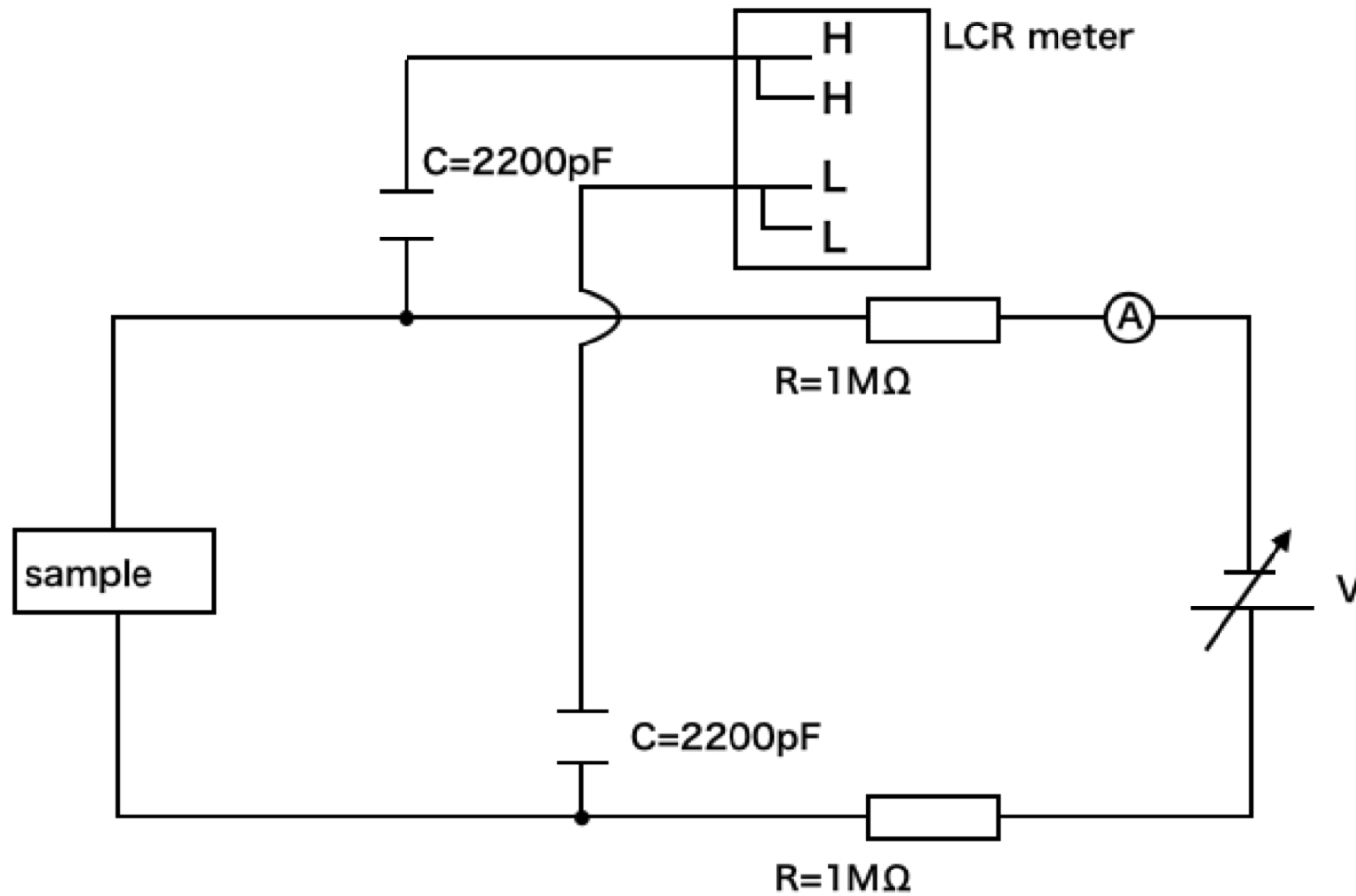


Summary

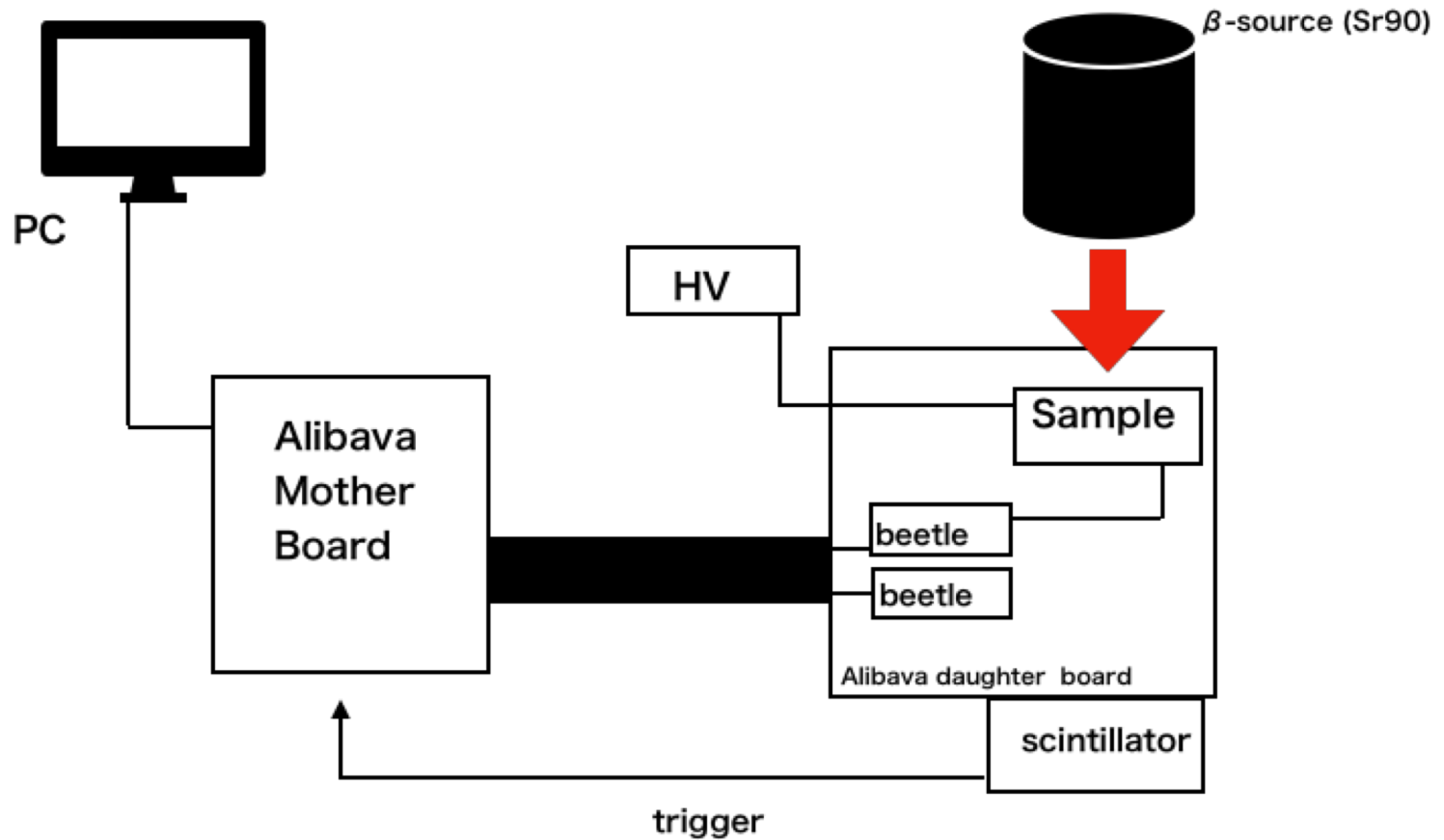
- We evaluated characteristics of HPK LGAD samples
 - IV
 - Thinner and high P+ dose -> gain @low voltage
 - Gain retains after γ -ray irradiation
 - After neutron irradiation, gain drops
 - Bulk Capacitance
 - Stepwise depletion progress is observed
 - Charge Collection
 - After neutron irradiation gain drops
-> need high voltage
 - Gain uniformity measured for strip LGAD
 - Irradiation induces gain in inter strip region
- We will evaluate from this test beam about ...
 - Time resolution (2x2 array pad)
 - Gain uniformity (strip)

back up

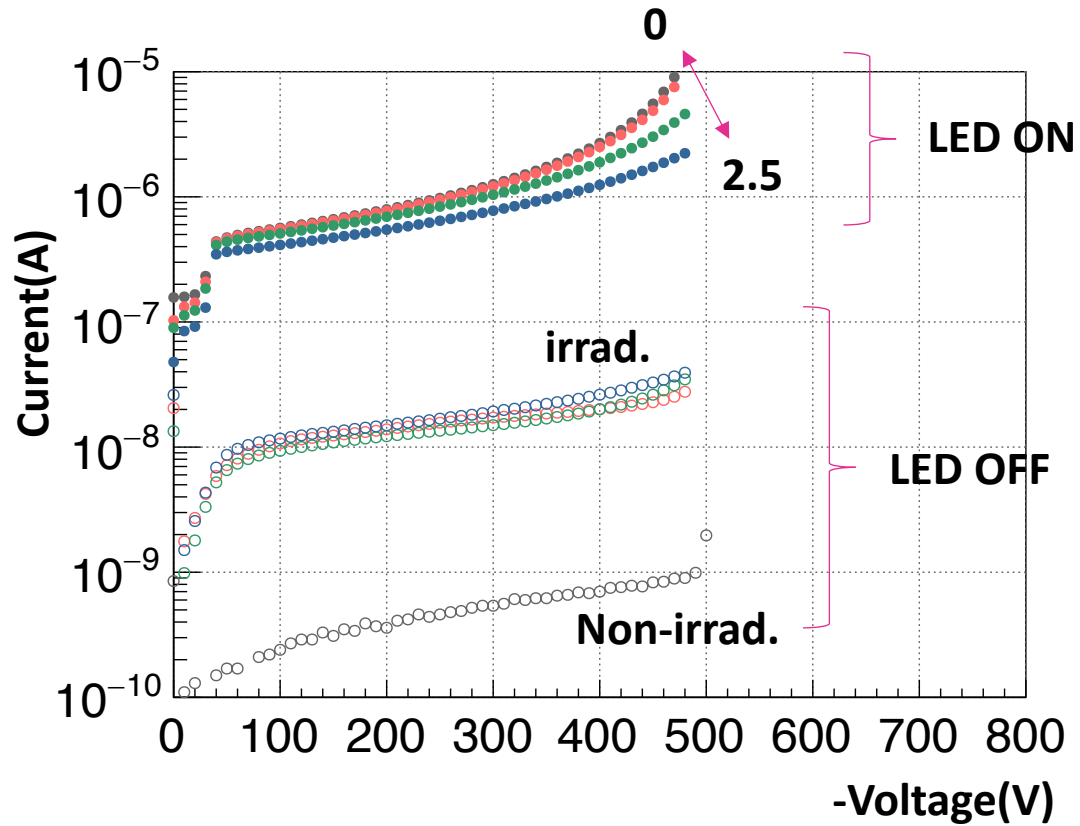
IV,CV Circuit



CC Circuit



γ - ray irradi. IV $80\mu\text{m}$



TB Set up

